



US 20020075910A1

(19) **United States**(12) **Patent Application Publication** (10) **Pub. No.: US 2002/0075910 A1**
(43) **Pub. Date: Jun. 20, 2002**(54) **WAVELENGTH MONITOR AND SEMICONDUCTOR LASER DEVICE**(76) **Inventors:** Masao Imaki, Tokyo (JP); Yoshihito Hirano, Tokyo (JP); Makoto Sato, Tokyo (JP); Kenji Masuda, Tokyo (JP); Akihiro Adachi, Tokyo (JP); Yasunori Nishimura, Tokyo (JP); Shinichi Takagi, Tokyo (JP)(30) **Foreign Application Priority Data**Dec. 6, 2000 (JP) 2000-371471
Apr. 27, 2001 (JP) 2001-132746**Publication Classification**(51) **Int. Cl.⁷** H01S 3/13; H01S 3/00; H01S 5/00
(52) **U.S. Cl.** 372/29.02; 372/43; 372/38.01**Correspondence Address:**Platon N. Mandros, Esq.
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Alexandria, VA 22313-1404 (US)(57) **ABSTRACT**

A wavelength monitor comprises a cylindrical lens configured to allow a laser beam emitted from a semiconductor laser to pass therethrough, first and second photodetectors configured to receive the laser beam through the cylindrical lens, and a wavelength filter disposed in an optical path between the semiconductor laser and the first photodetector.

(21) **Appl. No.:** 09/988,662
(22) **Filed:** Nov. 20, 2001